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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Seishiro Fujii et al. Art Unit : 1645
Serial No. : 10/664,795 Examiner : Unknown
Filed : September 19, 2003
Title : METHODS AND COMPOSITIONS FOR PREVENTING SKIN DAMAGE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before the receipt of a first Office action on the merits.

Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: May 20, 2004

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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 10287-077001		Application No. 10/664,795	
Supplemental Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))				Applicant Seishiro Fujii et al.			
				Filing Date September 19, 2003		Group Art Unit 1645	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,299,858	10/09/2001	Serbedzija et al.			
	AB						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AC							
	AD							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AE	
	AF	

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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	